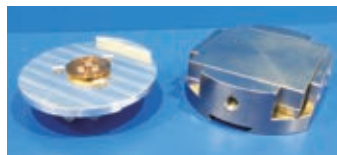


Hitachi FIB⇔FE-SEM compatible sample holder MI4050 ⇔ Regulus/SU8200/SU8000/etc.



Enhanced throughput for FIB milling and SEM imaging/analysis !

- Compatible sample holder allows single-action introduction of MI4050 sample stub to Hitachi FE-SEM.



FIB milling



Compatible sample holder



SEM imaging/analysis



FE-SEM : Field Emission Scanning Electron Microscope



Regulus
SU8200
SU8010
etc.